

<b>Notice of References Cited</b>	Application/Control No. 10/707,516	Applicant(s)/Patent Under Reexamination FAN ET AL.	
	Examiner MINH D. DAO	Art Unit 2618	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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	E	US-			
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	G	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 10290282 A	10-1998	Japan	INOUE, HIROYUKI	
	O	EP 682419 A2	11-1995	European Patent	SAWAHASHI et al.	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

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